

Challenges and Opportunities in Manufacturing 3-Dimensional Heterogeneously Integrated (3DHI) Microsystems

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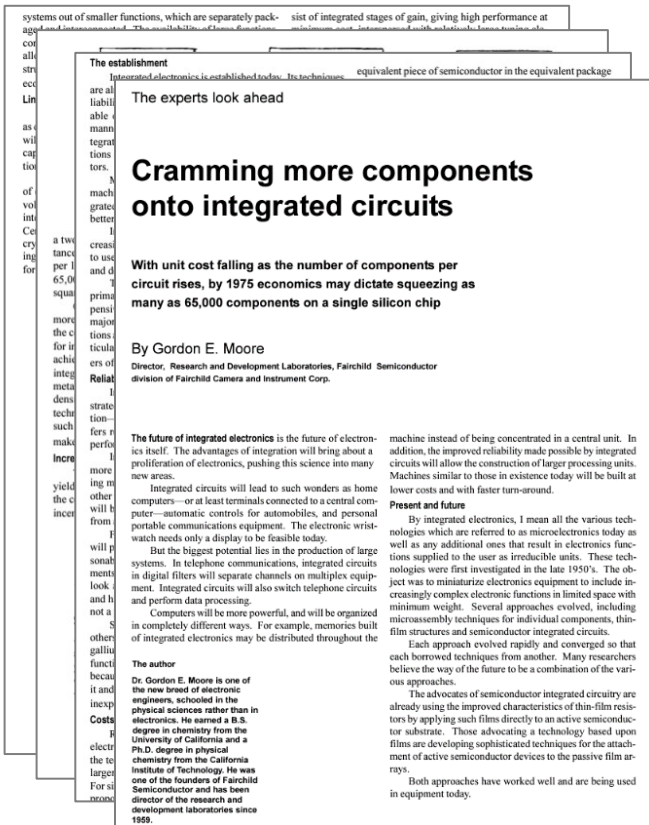
Briefing Prepared for Heterogeneous Integration Roadmap Meeting

February 22, 2024





Disaggregation*



Source: Electronics, Volume 38, Number 8, April 19, 1965

“It may prove more economical to **build large systems out of smaller functions, which are separately packaged and interconnected.** The availability of large functions, combined with functional design and construction, should allow the manufacturer of large systems to design and construct a considerable variety of equipment both rapidly and economically.”

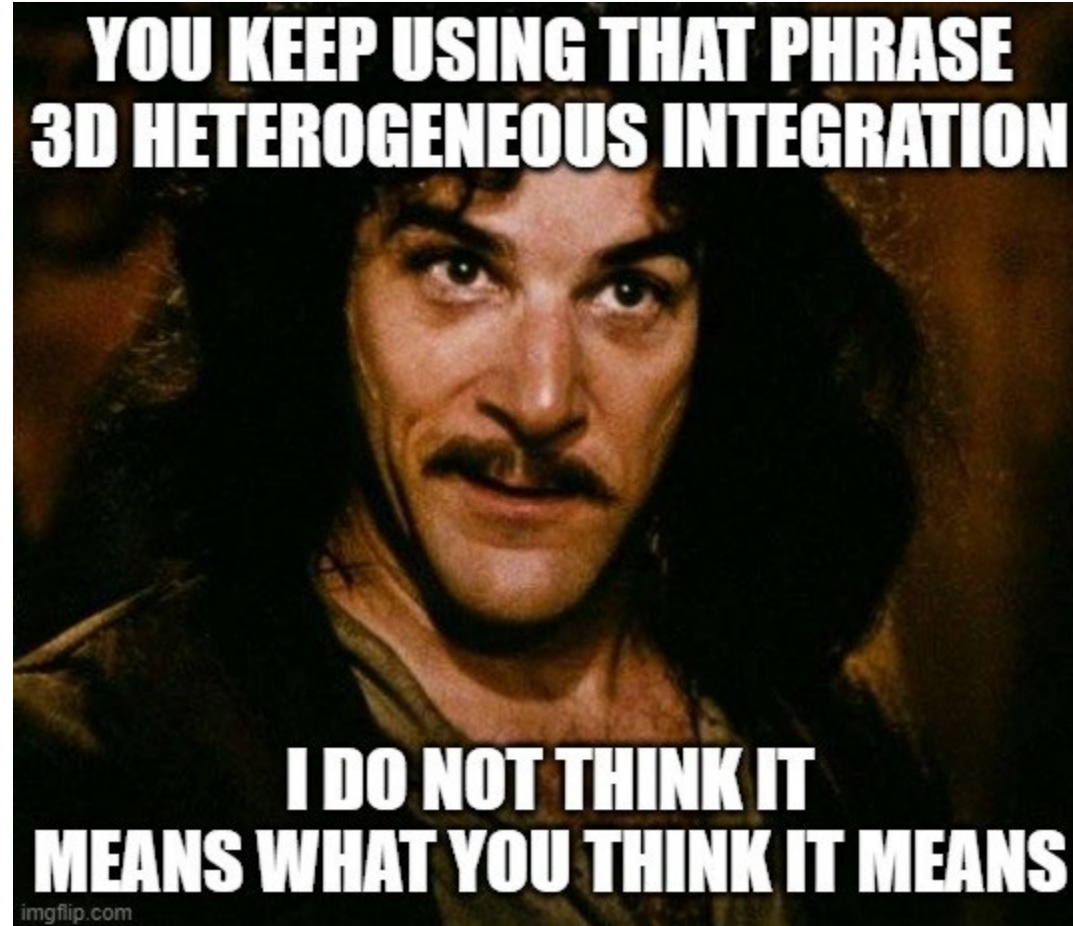
– Gordon Moore

*a.k.a.

- *Polyolithic*
- *Pseudo-lithic*
- *Chiplet-based*
- *3DHI*



What is 3DHI?



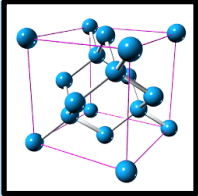
Source: <https://imgflip.com/memegenerator/Inigo-Montoya>



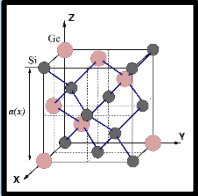
Heterogeneous Integration (HI) – Traditional Focus

Traditional Focus

Materials

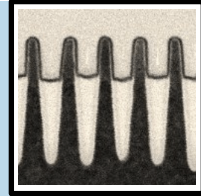


Silicon

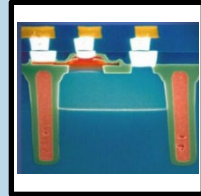


Silicon germanium

Devices

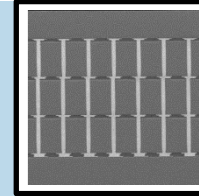


MOSFET, FinFET,
GAAFET

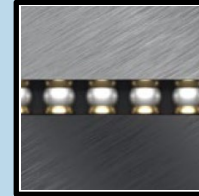


Bi-CMOS,
HBTs

Process

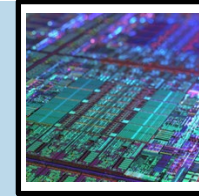


Bump,
 μ -Bump,
TSV, Hybrid

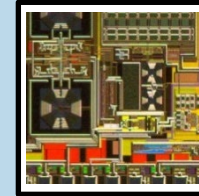


Bump,
 μ -Bump,
TSV, Hybrid

Function



Logic, Memory



Analog, Mixed-Signal,
RF

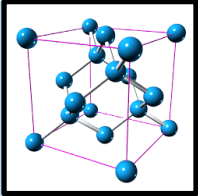
Traditional Focus

Materials

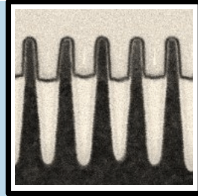
Devices

Process

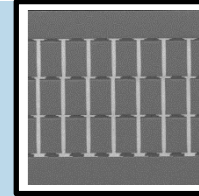
Function



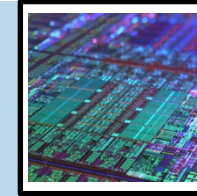
Silicon



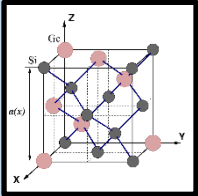
MOSFET, FinFET, GAAFET



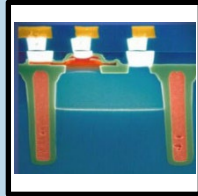
Bump, μ -Bump, TSV, Hybrid



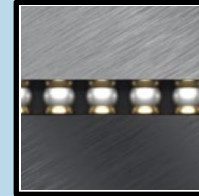
Logic, Memory



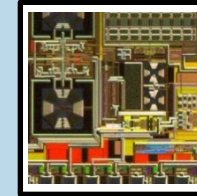
Silicon germanium



Bi-CMOS, HBTs

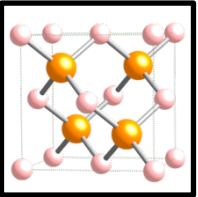


Bump, μ -Bump, TSV, Hybrid

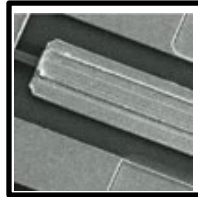


Analog, Mixed-Signal, RF

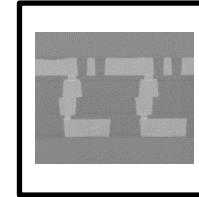
Emerging Opportunities



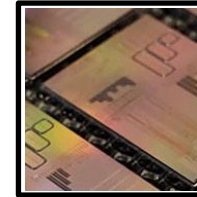
III-V, II-VI (GaAs, InP, HgCdTe)



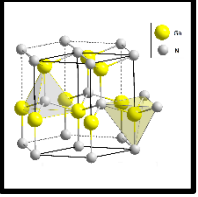
Laser, LED, Detector



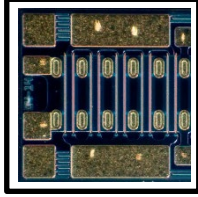
Bump, μ -Bump, TSV, Hybrid



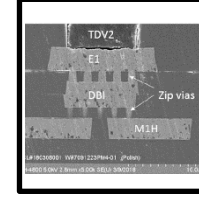
Photonics, RF



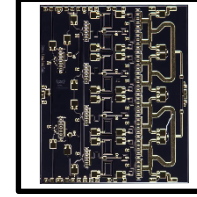
Wide bandgap (GaN, SiC)



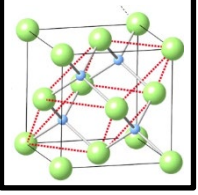
HEMT, MESFET, JFET



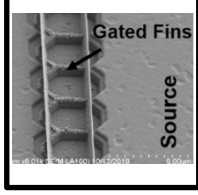
Bump, μ -Bump, TSV, Hybrid



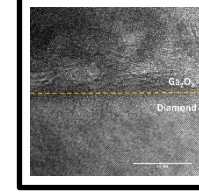
Photonics, RF, Power



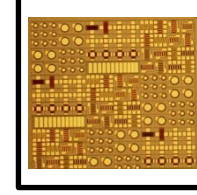
Ultrawide bandgap (AlGaN, Diamond)



HEMT, MESFET, JFET



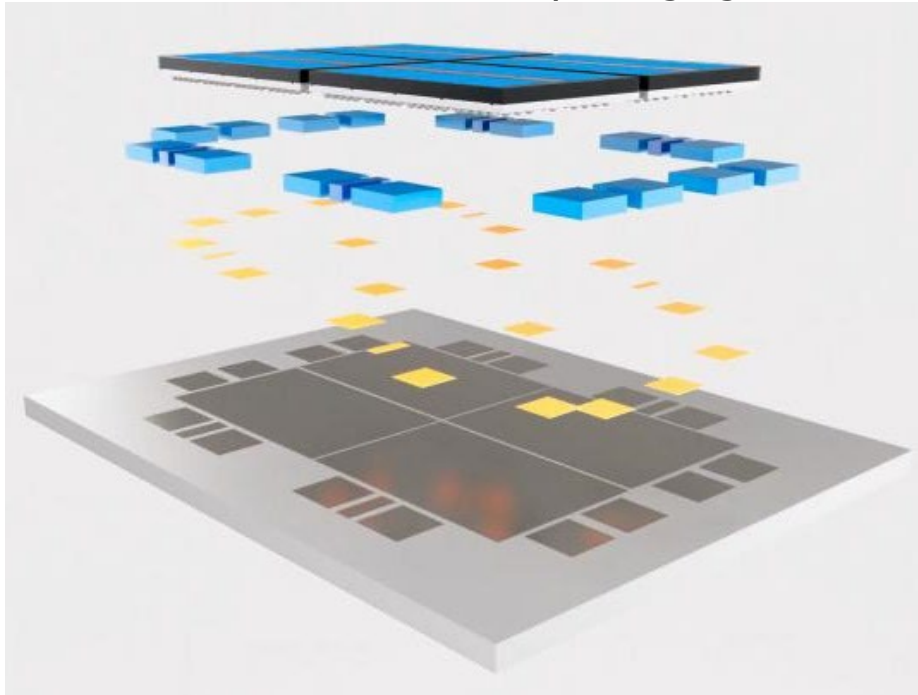
Bump, μ -Bump, TSV, Hybrid



Photonics, Power

3D

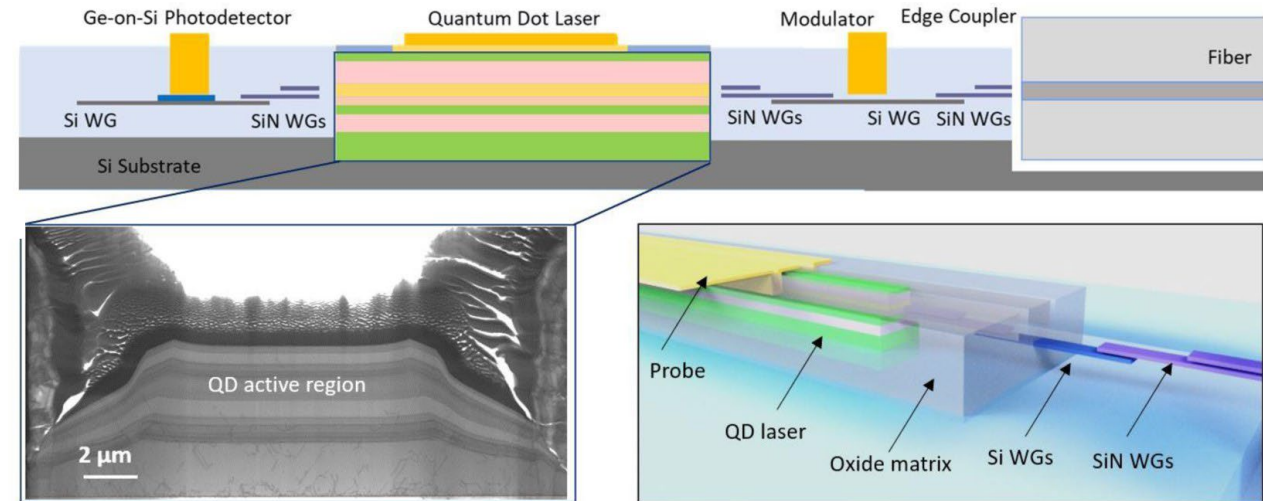
Intel 3D stacked packaging



Source: Intel

HI

High-performance lasers on a 300 mm silicon photonics wafer



Source: RF-SUNY, IQE, UCSB

3DHI: Three-dimensional heterogeneous integration
 Ge: Germanium
 QD: Quantum dot

Si: Silicon
 SiN: Silicon nitride
 WGs: Waveguides

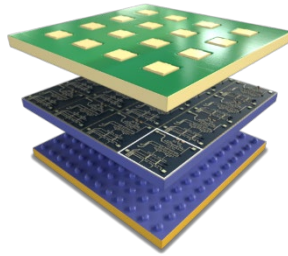


3DHI is across our current programs

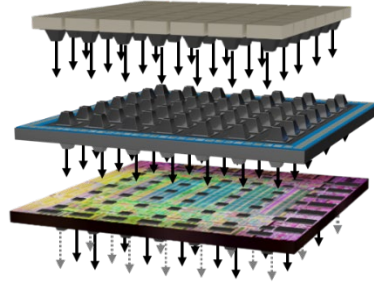
A-PhI



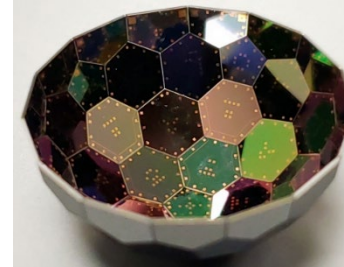
ELGAR



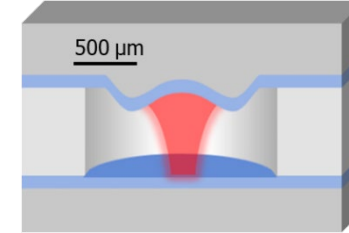
FENCE



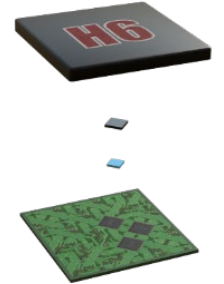
FOCII



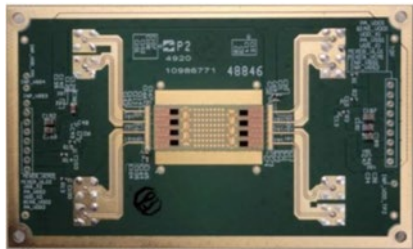
GRYPHON



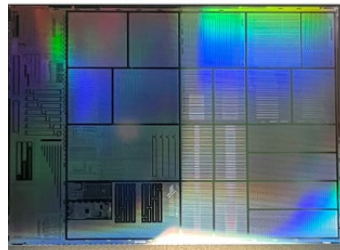
H6



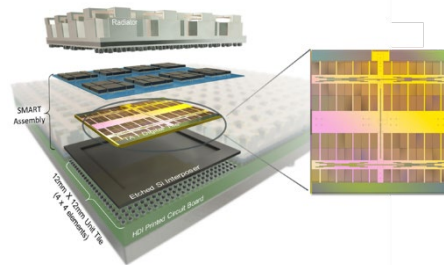
JUMP / JUMP 2.0



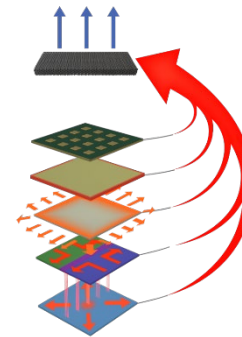
LUMOS



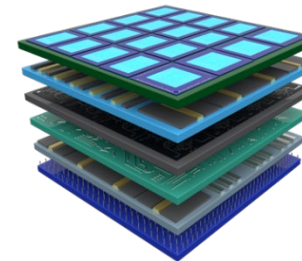
MIDAS



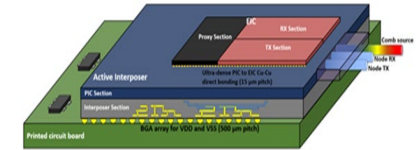
Minitherms3D



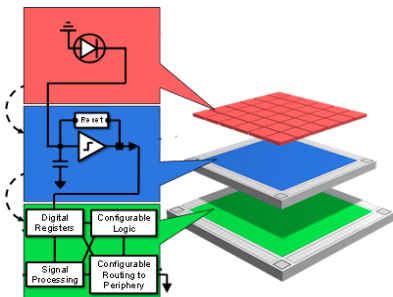
NGMM



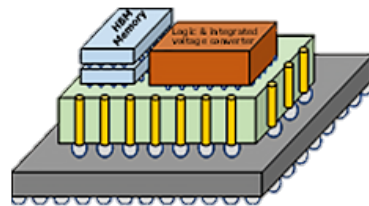
PIPES



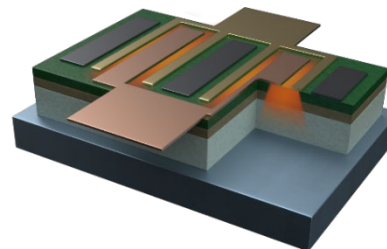
ReImagine



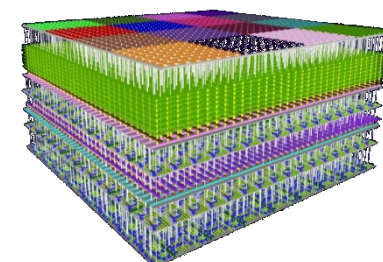
SPCE



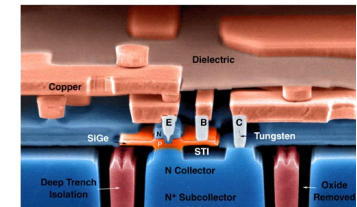
THREADS



3DSoc

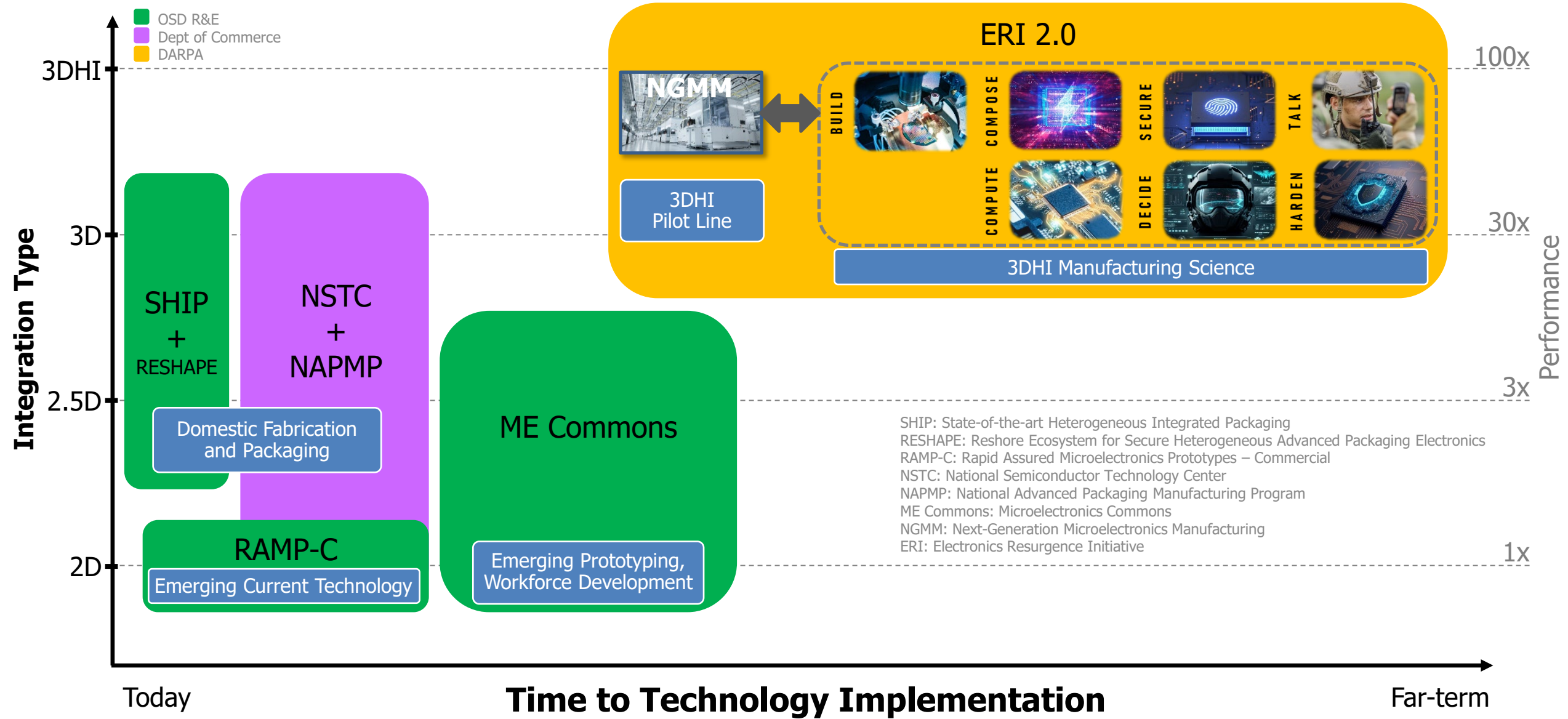


T-MUSIC





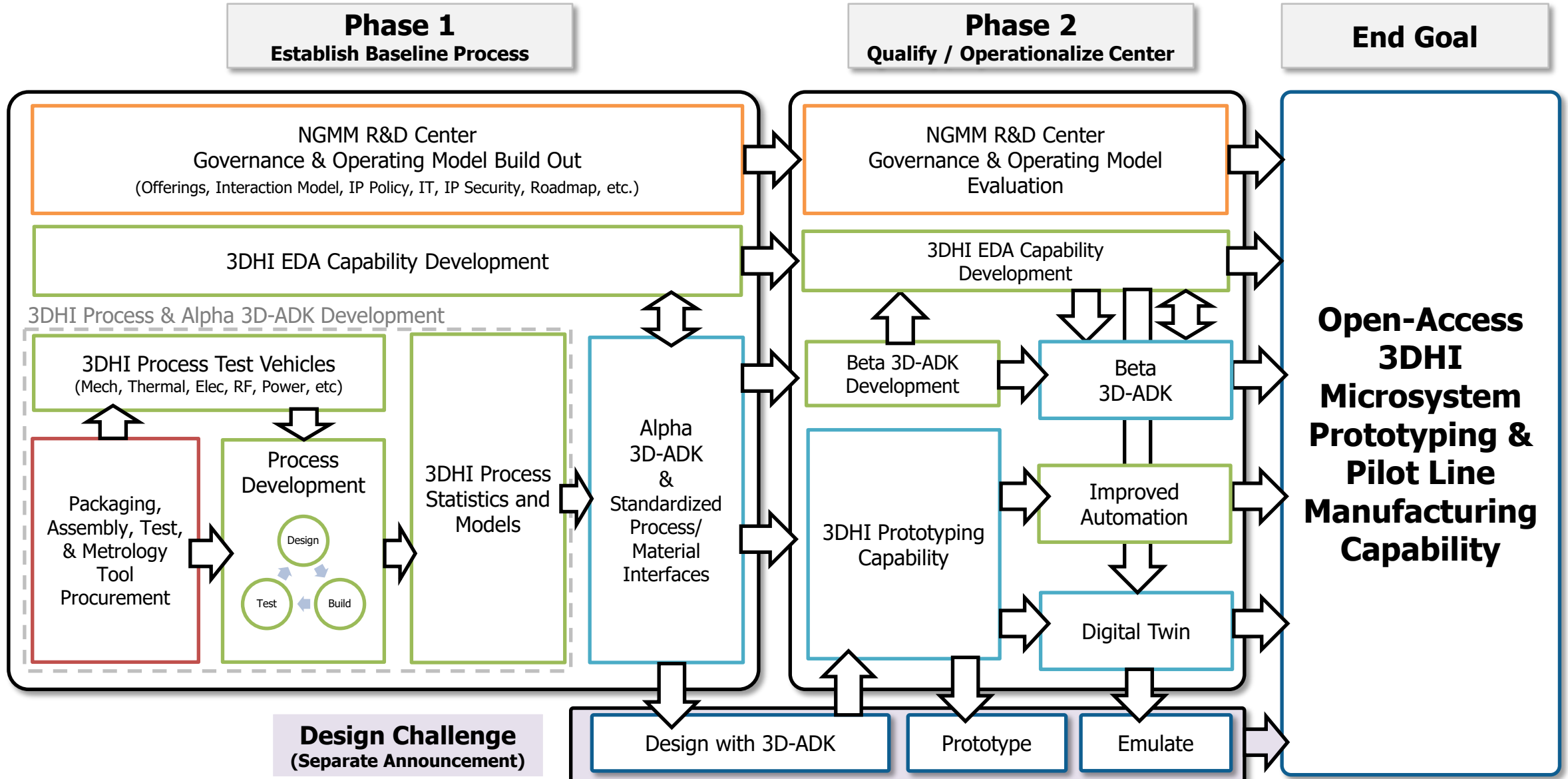
ERI 2.0: A long-term vision for advanced microelectronics manufacturing



SHIP: State-of-the-art Heterogeneous Integrated Packaging
 RESHAPE: Reshore Ecosystem for Secure Heterogeneous Advanced Packaging Electronics
 RAMP-C: Rapid Assured Microelectronics Prototypes – Commercial
 NSTC: National Semiconductor Technology Center
 NAPMP: National Advanced Packaging Manufacturing Program
 ME Commons: Microelectronics Commons
 NGMM: Next-Generation Microelectronics Manufacturing
 ERI: Electronics Resurgence Initiative



NGMM encompasses a multi-threaded approach for developing a 3DHI capability

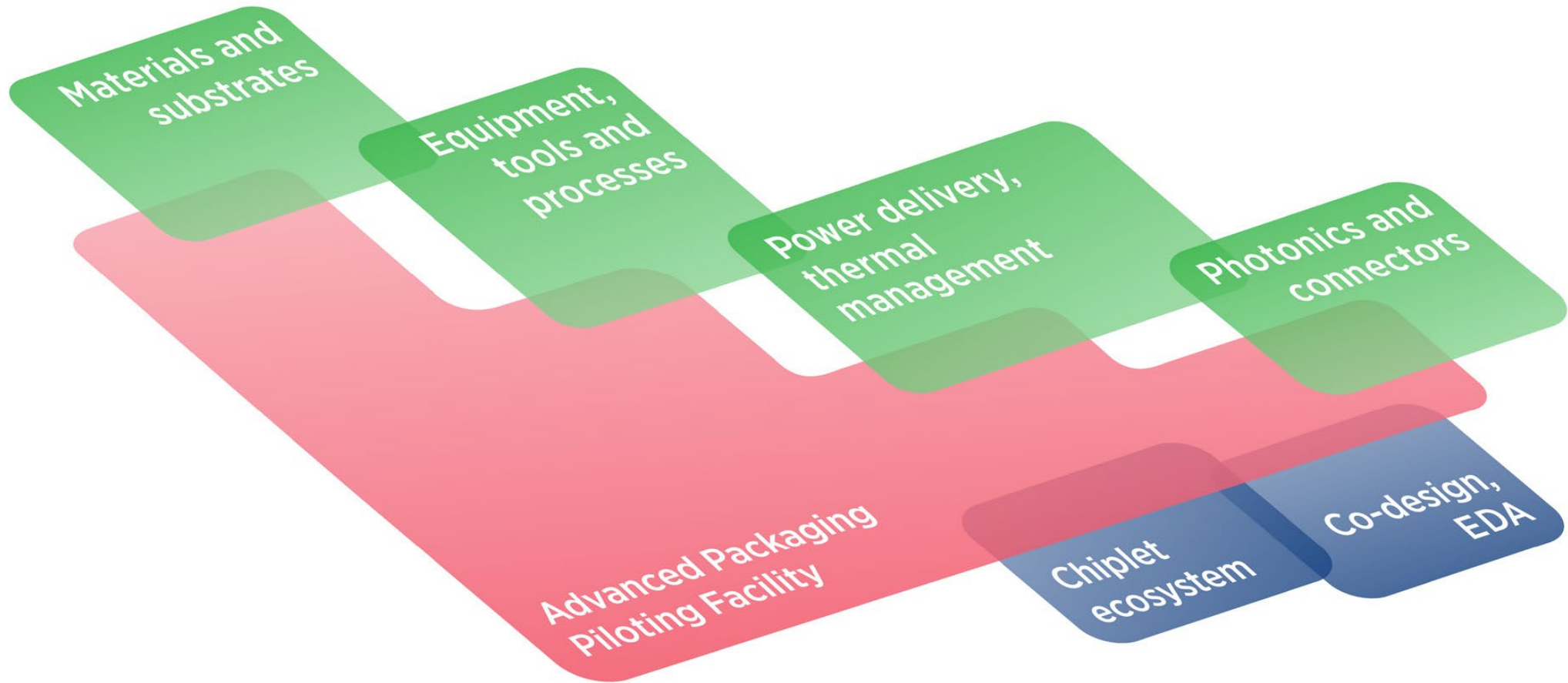




Process Modules	Test Vehicles	3D-ADK	EDA
<ul style="list-style-type: none">• Wafer post-processing• Bonding layer fabrication• Assembly• Technical challenges<ul style="list-style-type: none">• Dense, scaled interconnects• Standards for bonding layer interfaces• Thermal management• Diverse materials, including sub-200 mm wafers	<ul style="list-style-type: none">• Validate microsystem performance, including<ul style="list-style-type: none">• RF• Optical• Power• Thermal• Mechanical• Smaller sub-components of larger micro-system• Emphasized in Phase 1 for meeting interface metrics	<ul style="list-style-type: none">• Model and rule support required for EDA tools adapting to 3DHI methodology and requirements• 3D-ADK includes:<ul style="list-style-type: none">• Process design rules• Assembly design rules• Stack specifications, including material properties and dimensions• Device and interconnect models	<ul style="list-style-type: none">• Adapt conventional capabilities to 3DHI microsystems• Broad access<ul style="list-style-type: none">• Support open data formats• Provide modular architecture to support third-party simulation tools• By Phase 2, develop digital twin of a placed and routed 3DHI circuit to model circuit behavior



CHIPS National Advanced Packaging & Manufacturing Program Vision



Technology investments are in green. Ecosystem investments are in blue.
The piloting facility, in red, will provide opportunities to validate new technologies for transition to U.S. manufacturing

Source: <https://www.nist.gov/system/files/documents/2023/11/19/NAPMP-Vision-Paper-20231120.pdf>



Challenge – the Domestic Cost Differential

WWHA – What Would Heilmeier Ask?

- H1 – What are you trying to do?
- H2 – How is it done today and who does it? What are the limitations to the present approaches?
 - What is “it”?
 - How is “it” done today (name and concise description)?
 - What is the definition, description, and rationale for each technical challenge to fully describe the H2 limitations?
- H3 – What is new about our approach and why do we think it will succeed?
 - What is the name, description, and novelty of the technical approach?
 - What are the insights, rationale, and supporting evidence that the technical approach will overcome the technical challenge?
- H4 – If we succeed, what difference will it make?
 - What is the mission capability that will be enabled?
 - What is the description and CONOPS*, significance, and relevance to the specific mission capability?
- H5 – How long do we think it will take? What are our mid-term/final exams? How much will it cost?

*CONOPS – Concept of Operations



Challenge – the Domestic Cost Differential

WWHA – What Would Heilmeier Ask?

- H1 – What are you trying to do? **Bring the costs for domestic packaging to $\leq 1.1X$ overseas packaging costs**
- H2 – How is it done today and who does it? What are the limitations to the present approaches?
 - What is “it”?
 - How is “it” done today (name and concise description)?
 - What is the definition, description, and rationale for each technical challenge to fully describe the H2 limitations?
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*CONOPS – Concept of Operations



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